

HPK31\_1

Bad Bump Test (through noise at BV = -2V)

chip number

16

15

14

13

12

11

10

9

columns

118

60

0

60

0

60

0

60

0

60

0

60

0

60

0

60

0

60

0

rows

0

5

10

15

15

10

5

0

columns

0

60

0

60

0

60

0

60

0

60

0

60

0

60

0

60

0

60

118

chip number

1

2

3

4

5

6

7

8

is bad bump

1.0

0.8

0.6

0.4

0.2

0.0

